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H01L 23/49816; H01L 23/5387; H01L
2224/32145

See application file for complete search history.

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- Primary Examiner* — Jasmine Clark

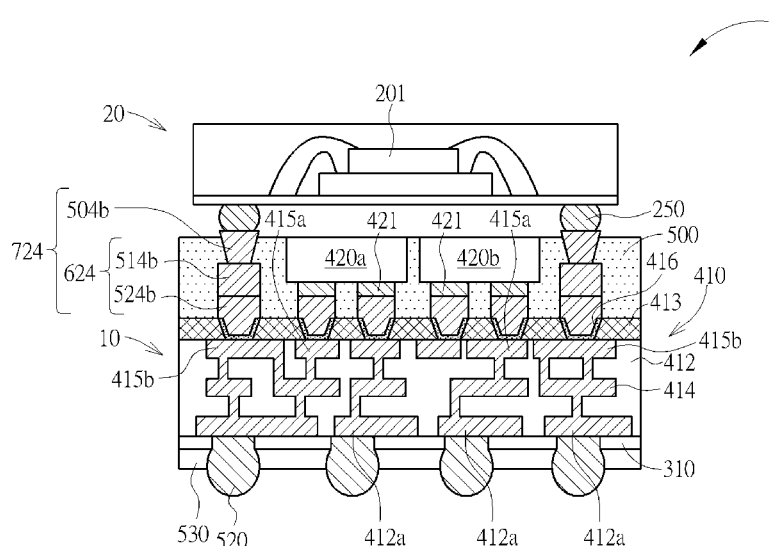
- (74) *Attorney, Agent, or Firm* — Winston Hsu; Scott Margo

- (57) **ABSTRACT**

- A package-on-package (PoP) assembly includes a bottom die package and a top die package mounted on the bottom die package. The bottom die package includes an interposer having a first side and a second side opposite to the first side, at least one chip mounted on the first side within a chip mounting area through a plurality of bumps, a molding compound disposed on the first side, the molding compound covering the at least one chip, and a plurality of peripheral bump structures penetrating through the molding compound within the peripheral area. Each of the peripheral bump structures includes conductive pillar and a partial TMV directly stacked on the conductive pillar. A plurality of solder balls is mounted on the second side of the interposer. The top die package is electrically connected to the peripheral bump structures.

- (58) **Field of Classification Search**
CPC H01L 25/0657; H01L 25/117; H01L
25/043; H01L 25/0756; H01L 2224/023;
H01L 2224/06167; H01L 2224/06182; H01L
2224/06187; H01L 2225/06503; H01L
2225/06562; H01L 2225/1058; H01L
2225/1041; H01L 25/03; H01L 2225/06586;
H01L 2224/12105; H01L 23/3121; H01L

9 Claims, 16 Drawing Sheets



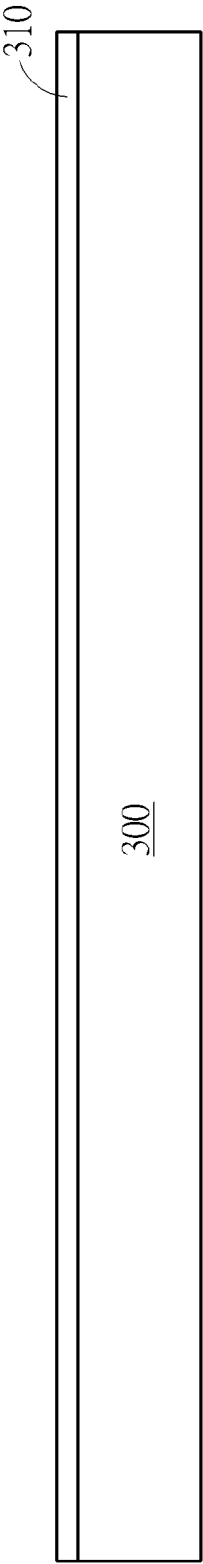


FIG. 1

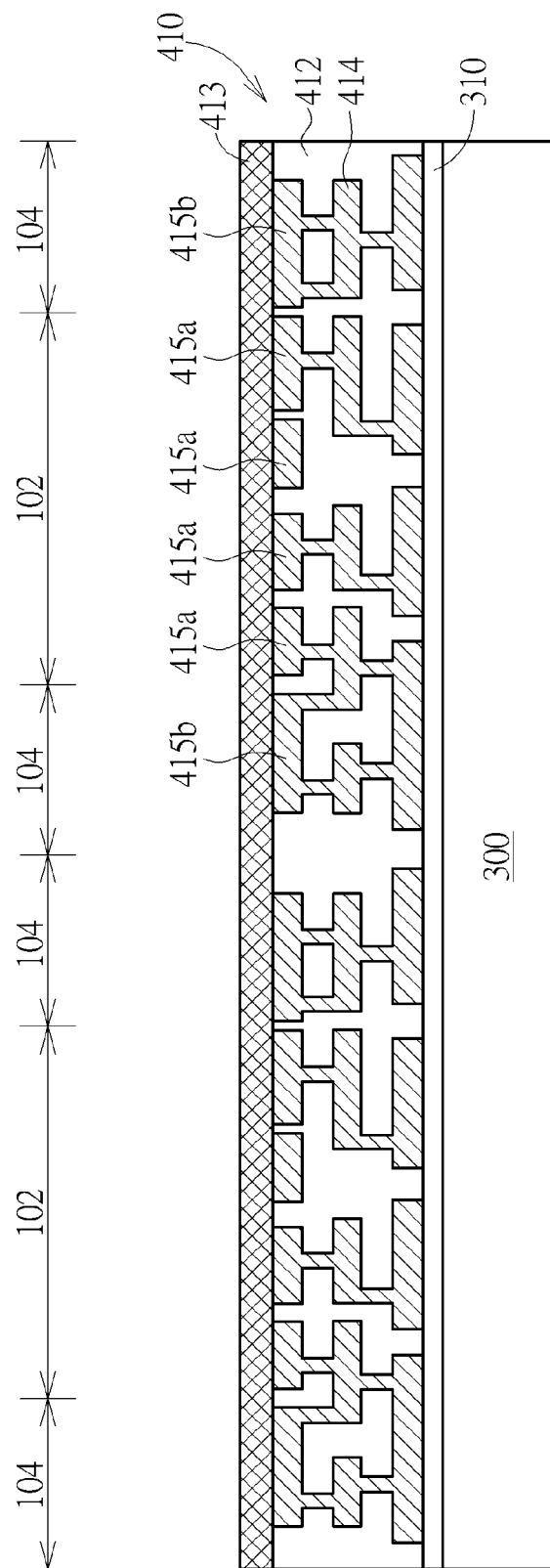


FIG. 2

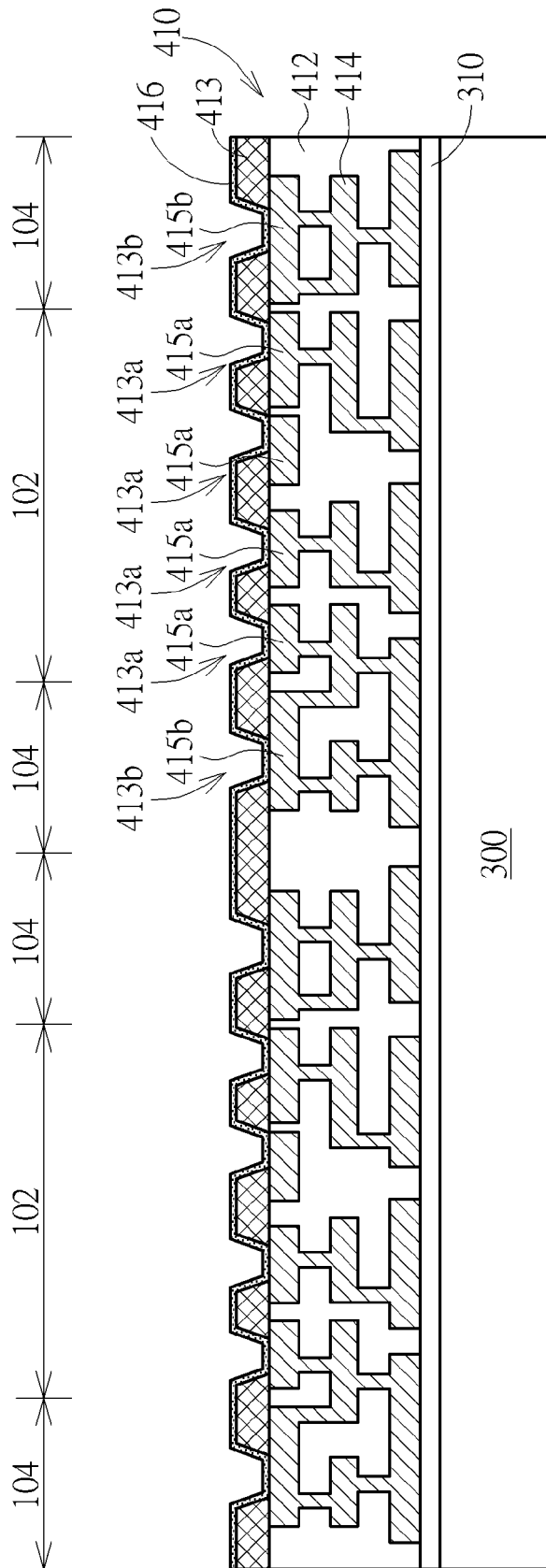


FIG. 3

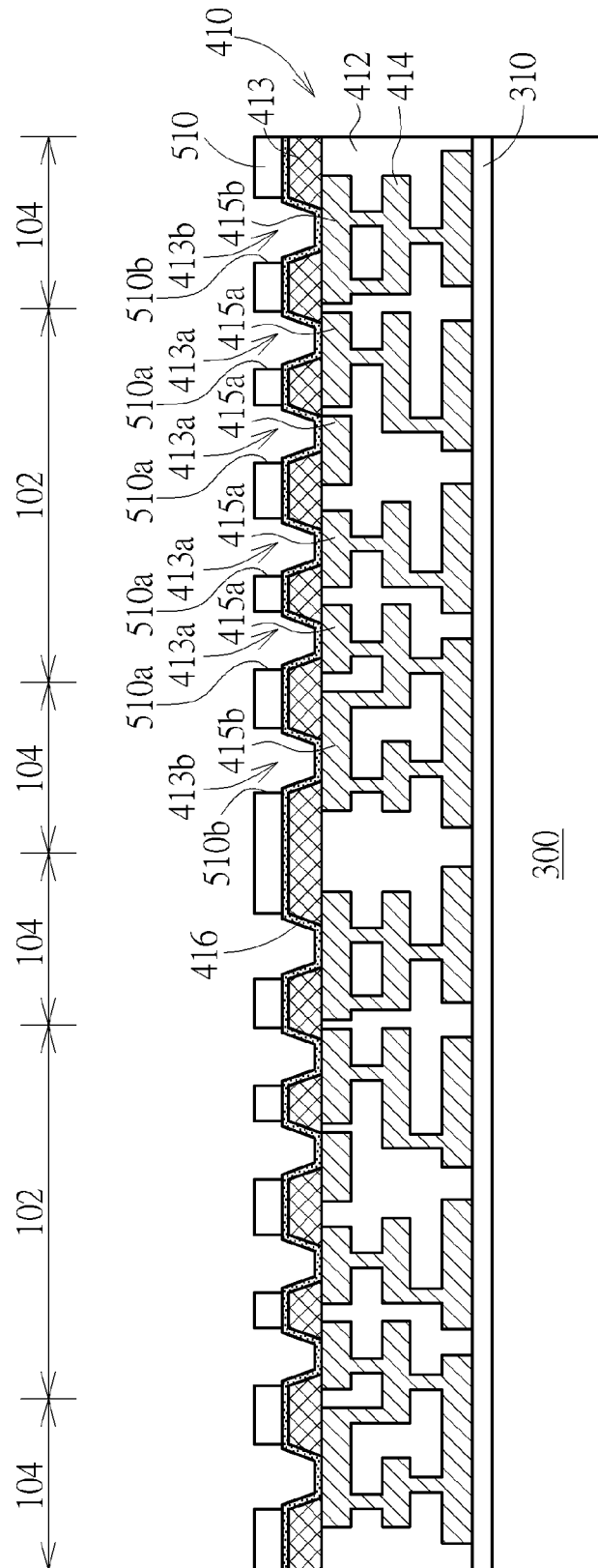


FIG. 4

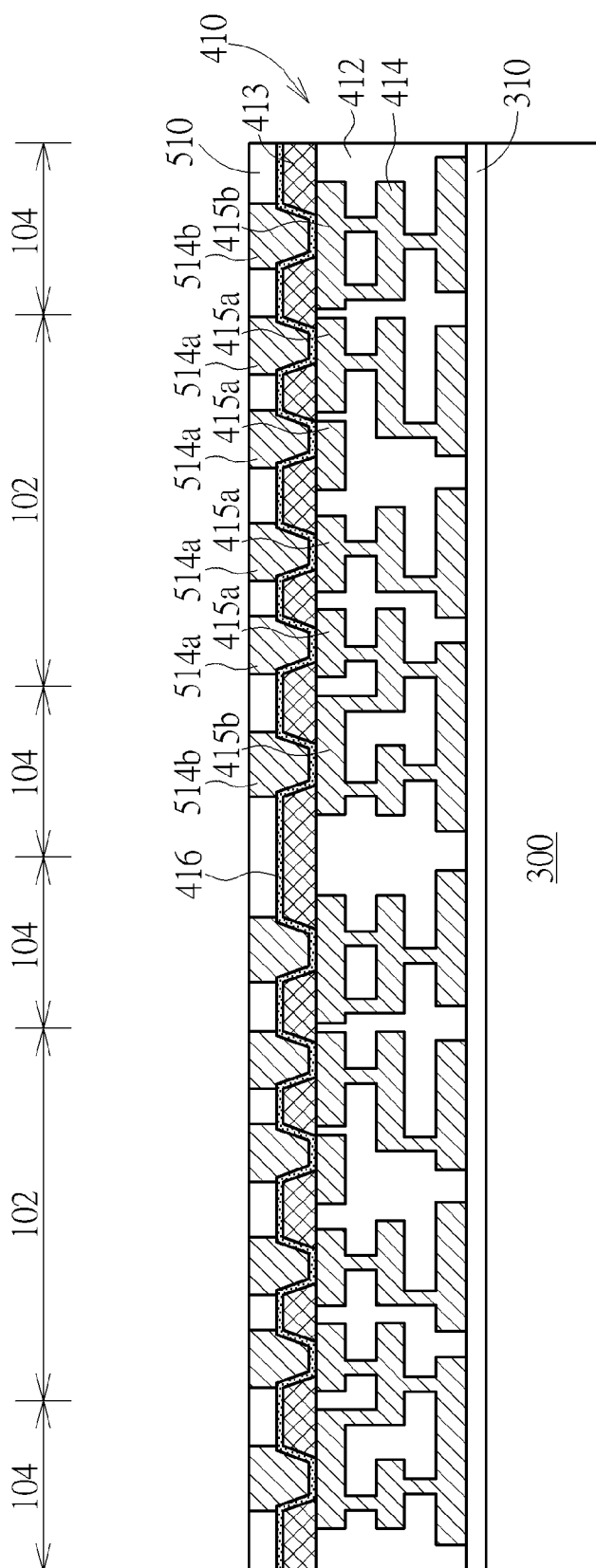


FIG. 5

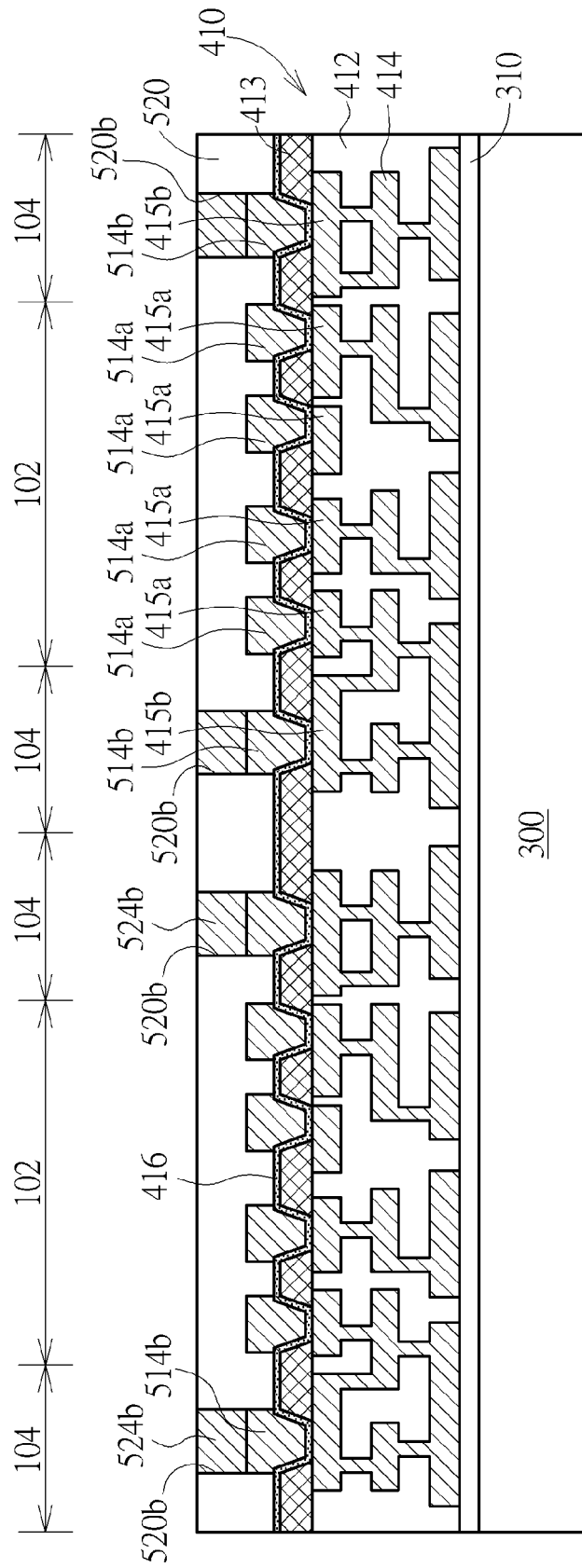


FIG. 7

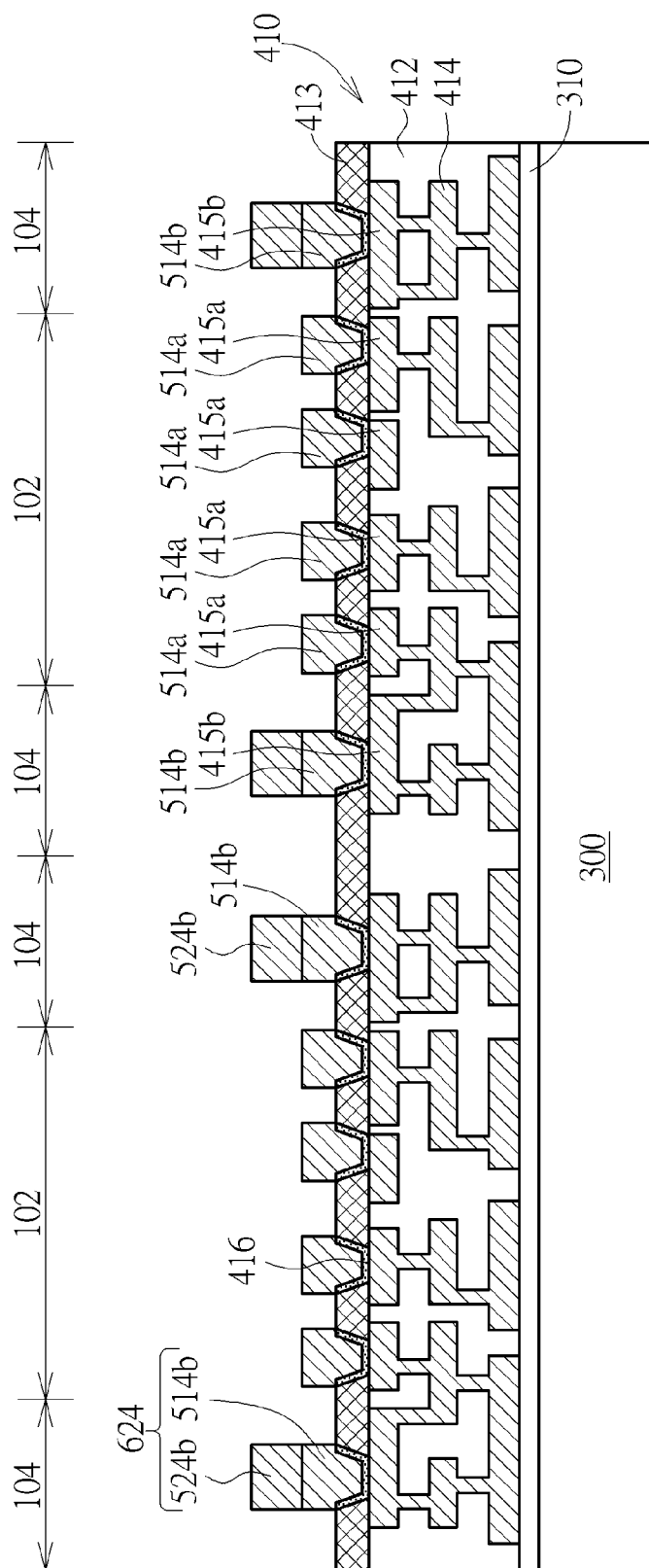


FIG. 8

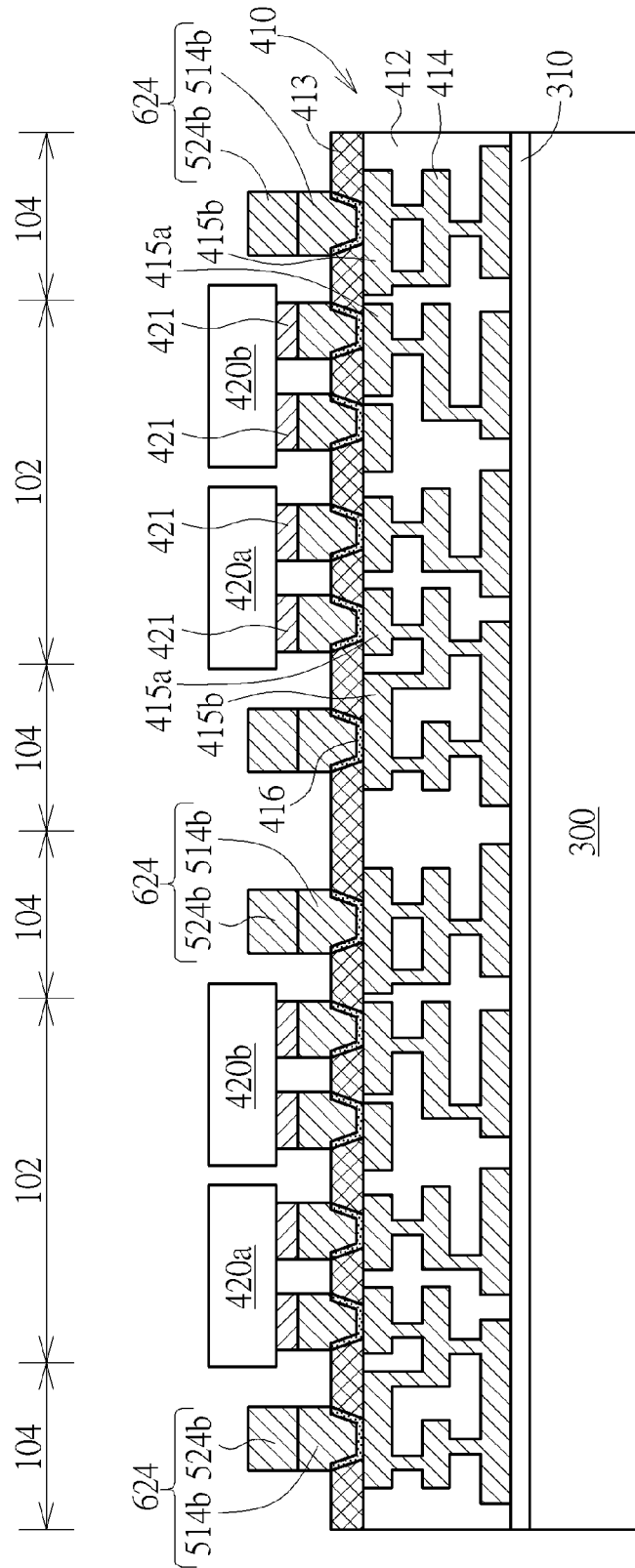


FIG. 9

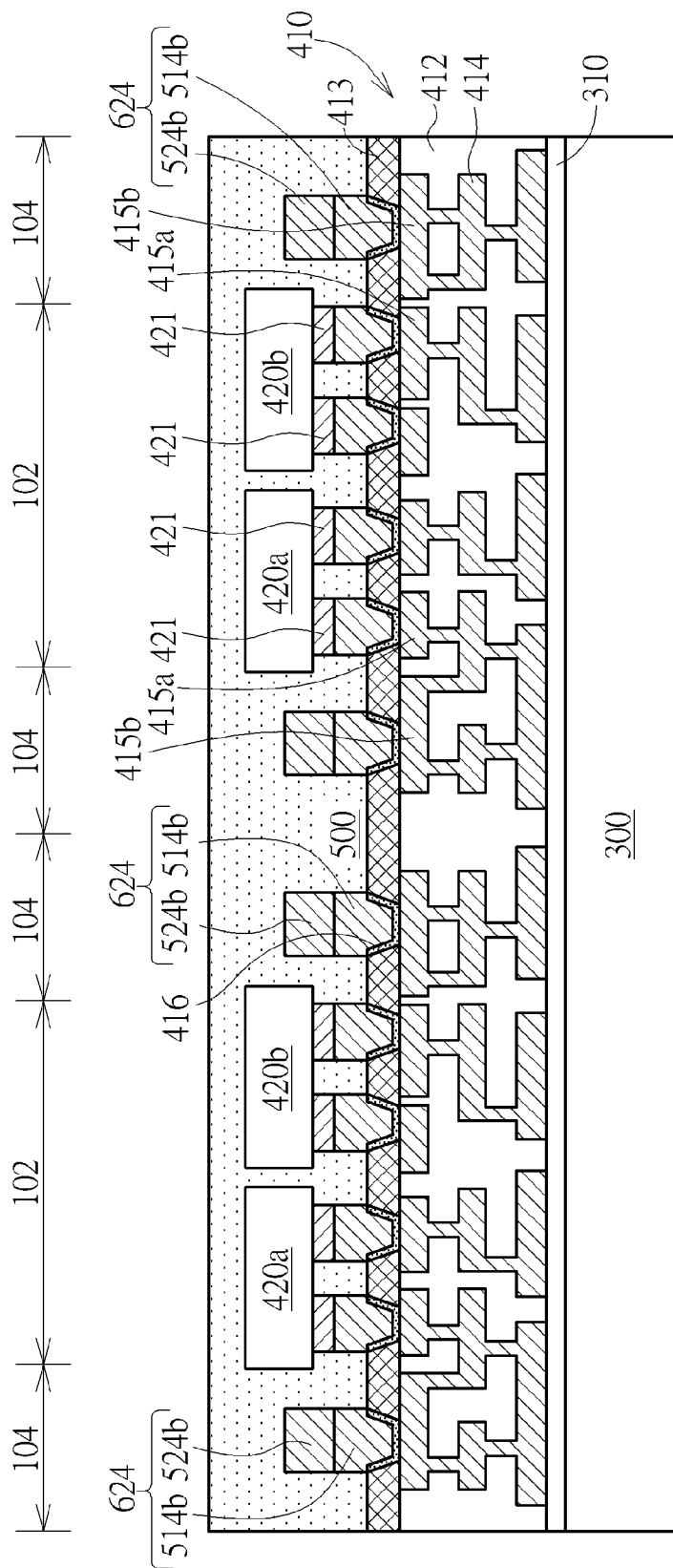


FIG. 10

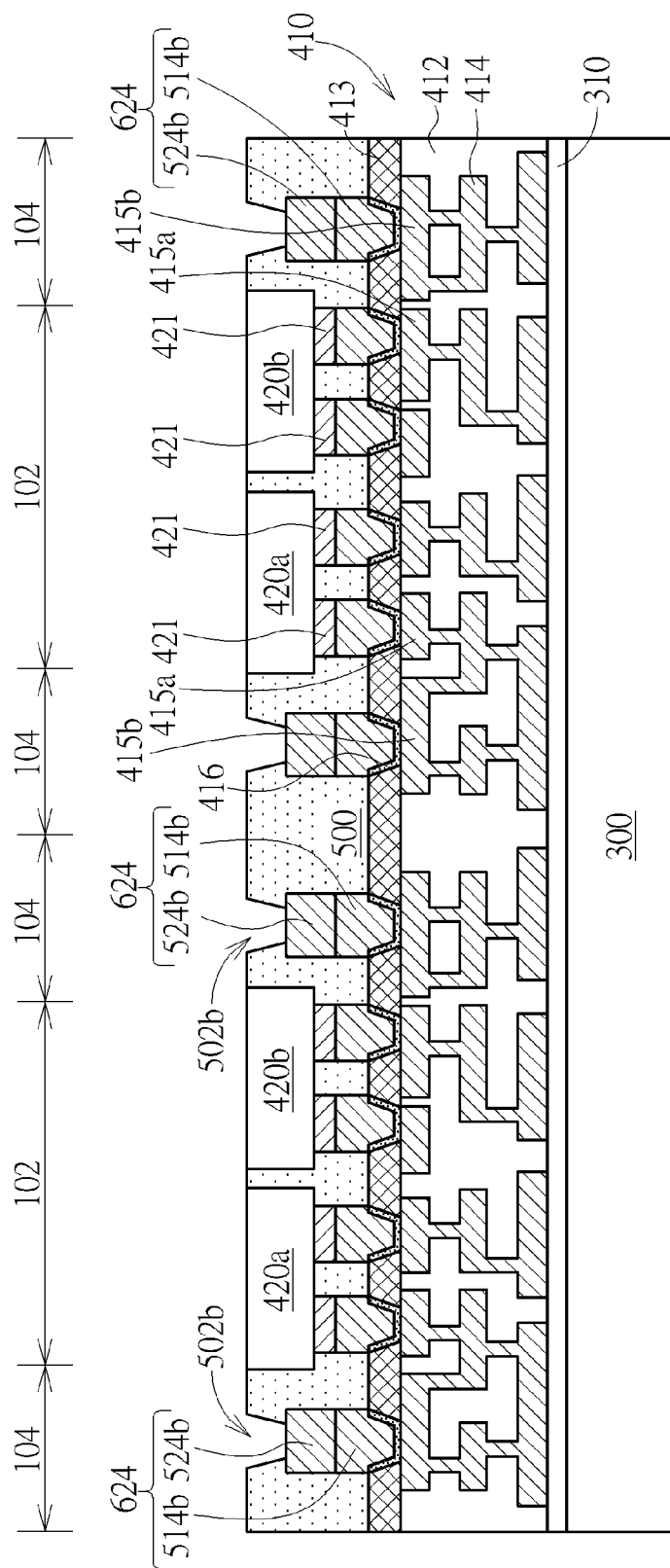


FIG. 11

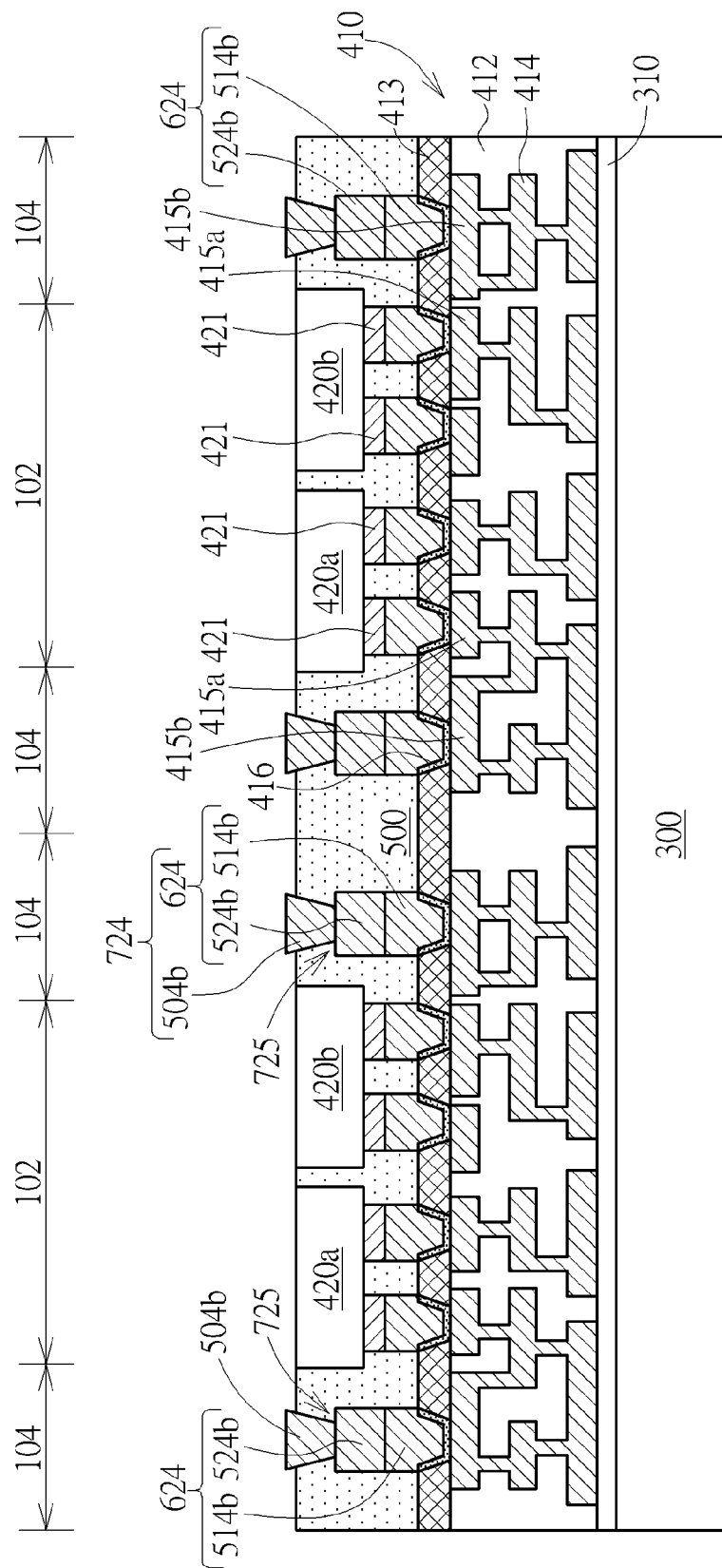


FIG. 12

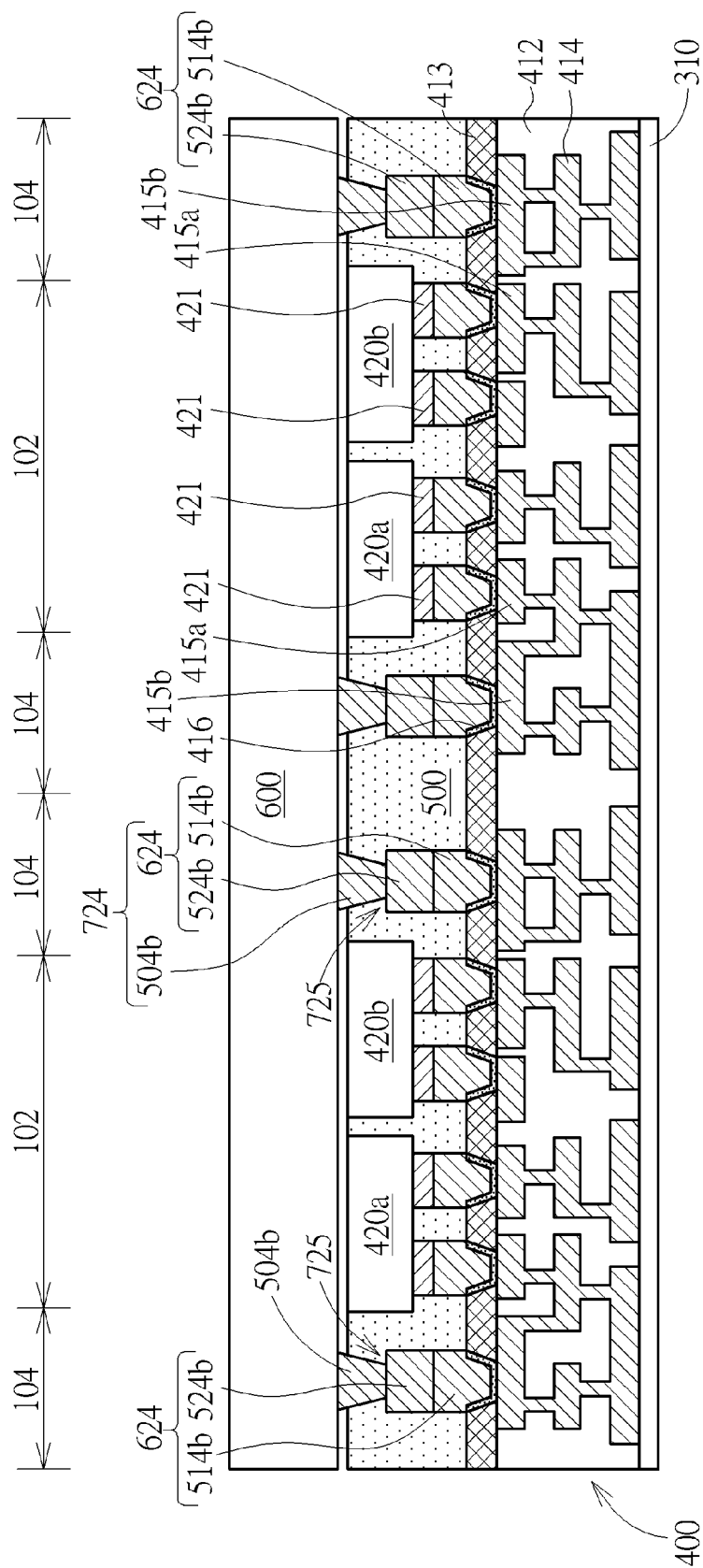


FIG. 13

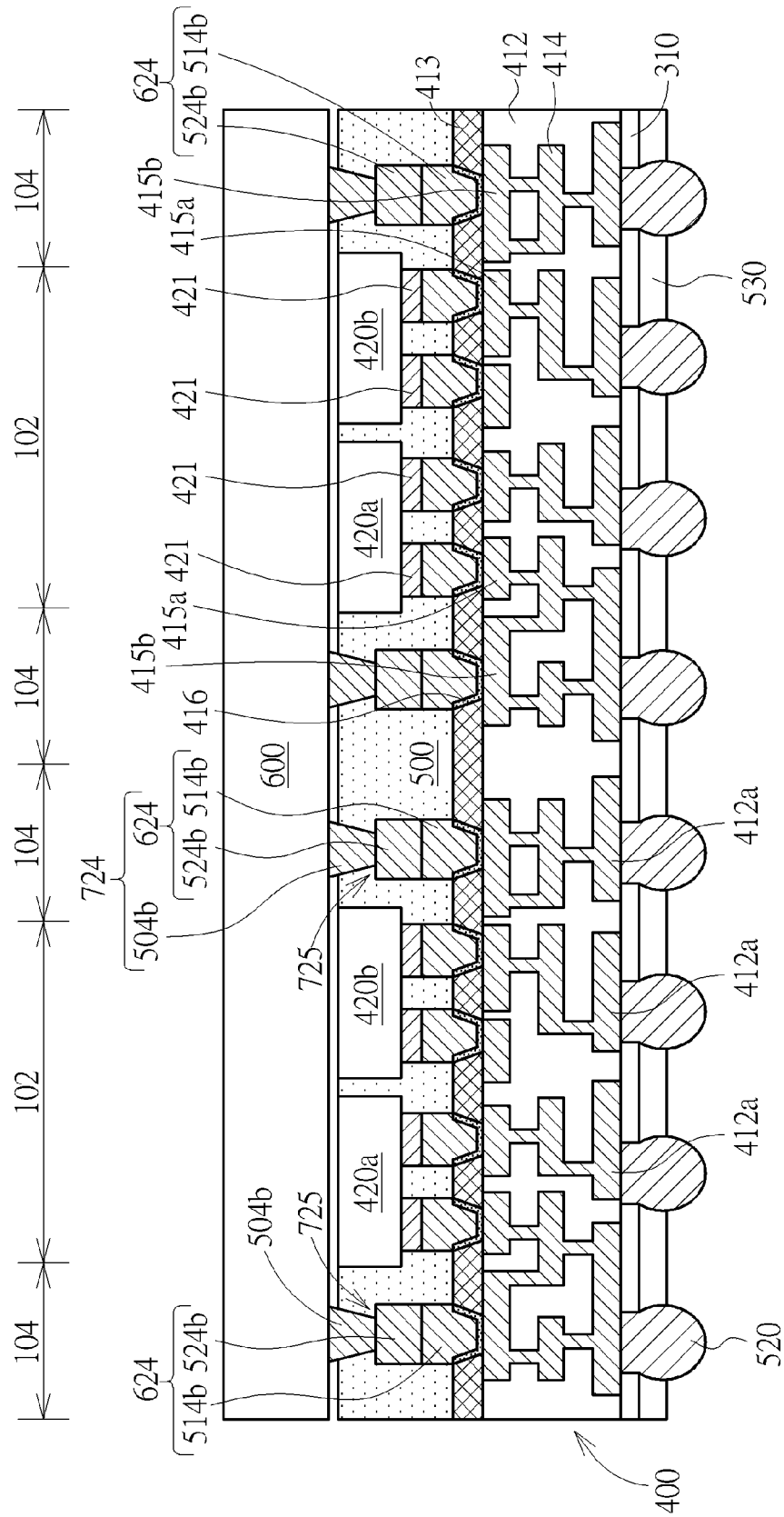


FIG. 14

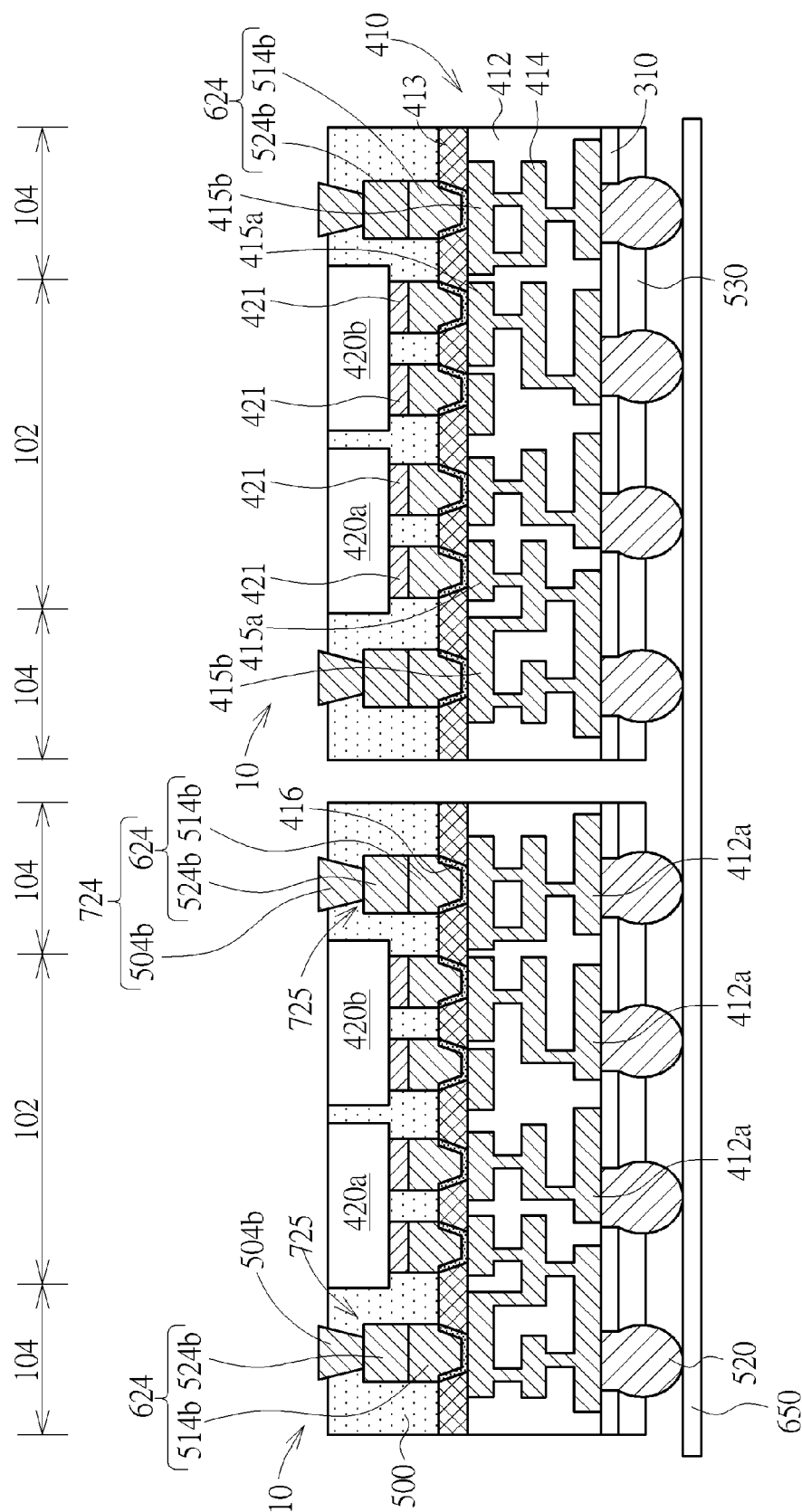


FIG. 15

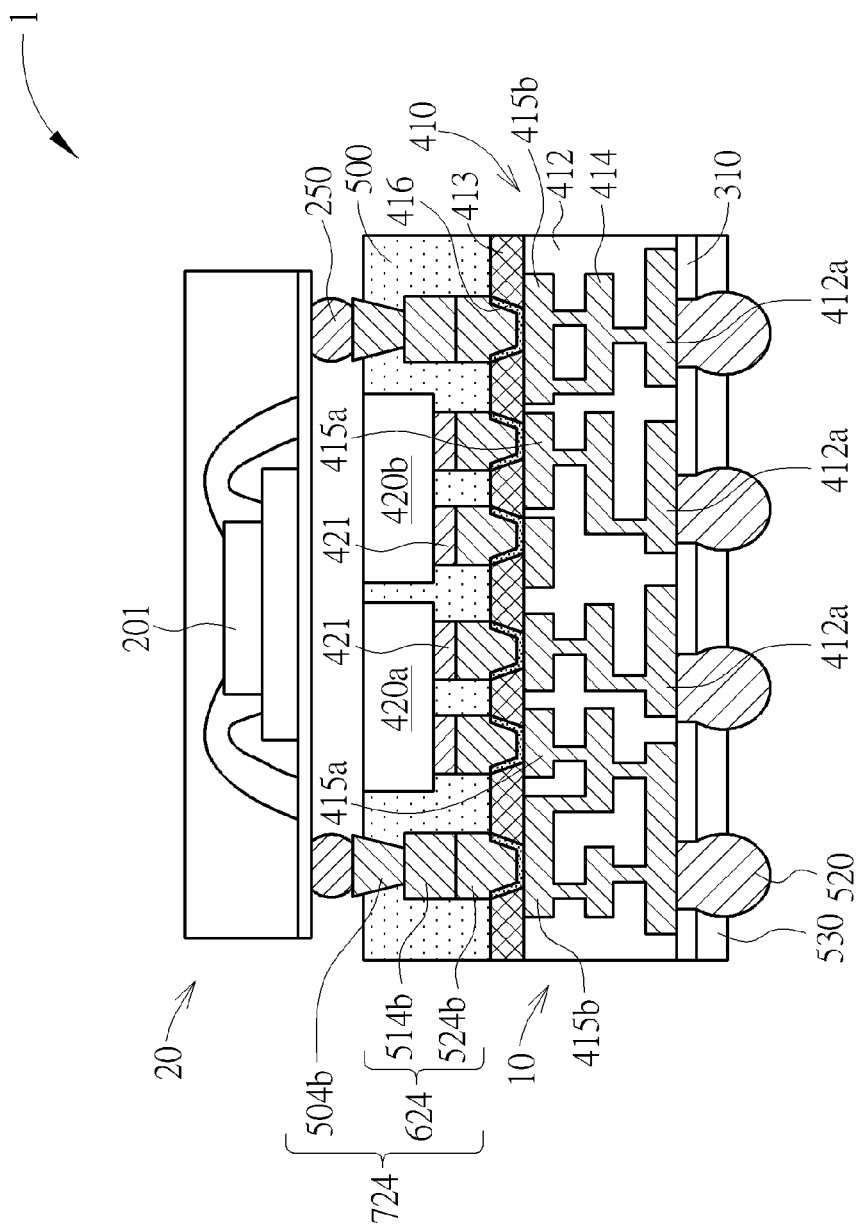


FIG. 16

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PACKAGE-ON-PACKAGE ASSEMBLY AND METHOD FOR MANUFACTURING THE SAME

BACKGROUND OF THE INVENTION

1. Field of the Invention

The present disclosure relates generally to the field of semiconductor packaging, and more particularly to a Package-on-Package (PoP) assembly and a method for manufacturing the same.

2. Description of the Prior Art

With recent advancements in the semiconductor manufacturing technology microelectronic components are becoming smaller and circuitry within such components is becoming increasingly dense. To reduce the dimensions of such components, the structures by which these components are packages and assembled with circuit boards must become more compact.

In order to meet the requirements of smaller footprints with higher densities, 3D stacking packaging such as PoP (Package-on-Package) assembly has been developed. Typically, a PoP assembly includes a top package with a semiconductor die bonded to a bottom package with another device die. In PoP designs, the top package may be interconnected to the bottom package through peripheral solder balls or through mold vias (TMVs).

However, the prior art PoP assembly is not able to provide very tight pitch stacking. Further, the prior art PoP assembly has large package form factor and poor warpage control. There is a need in this industry to provide a thin and fine pitch PoP assembly with reduced form factor and manufacture method thereof.

SUMMARY OF THE INVENTION

One object of the present disclosure is to provide a semiconductor device having package-on-package (PoP) configuration.

In one aspect of the disclosure, a package-on-package (PoP) assembly includes a bottom die package and a top die package mounted on the bottom die package. The bottom die package includes an interposer having a first side and a second side opposite to the first side, at least one chip mounted on the first side within a chip mounting area through a plurality of bumps, a molding compound disposed on the first side, the molding compound covering the at least one chip, and a plurality of peripheral bump structures penetrating through the molding compound within the peripheral area. Each of the peripheral bump structures includes a conductive pillar and a partial TMV directly stacked on the conductive pillar. A plurality of solder balls is mounted on the second side of the interposer. The top die package is electrically connected to the peripheral bump structures. An undercut is present between the third conductive stud and the second conductive stud.

These and other objectives of the present invention will no doubt become obvious to those of ordinary skill in the art after reading the following detailed description of the preferred embodiment that is illustrated in the various figures and drawings.

BRIEF DESCRIPTION OF THE DRAWINGS

The accompanying drawings are included to provide a further understanding of the embodiments, and are incorporated in and constitute apart of this specification. The

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drawings illustrate some of the embodiments and, together with the description, serve to explain their principles. In the drawings:

FIG. 1 to FIG. 16 are schematic, cross-sectional diagrams showing an exemplary method for fabricating a package-on-package (PoP) assembly according to one embodiment of the invention.

DETAILED DESCRIPTION

In the following detailed description of the invention, reference is made to the accompanying drawings, which form a part hereof, and in which is shown, by way of illustration, specific embodiments in which the invention may be practiced. These embodiments are described in sufficient detail to enable those skilled in the art to practice the invention. Other embodiments may be utilized and structural changes may be made without departing from the scope of the present invention.

The following detailed description is, therefore, not to be taken in a limiting sense, and the scope of the present invention is defined only by the appended claims, along with the full scope of equivalents to which such claims are entitled.

One or more implementations of the present invention will now be described with reference to the attached drawings, wherein like reference numerals are used to refer to like elements throughout, and wherein the illustrated structures are not necessarily drawn to scale. The terms “die”, “semiconductor chip”, and “semiconductor die” are used interchangeably throughout the specification.

Please refer to FIG. 1 to FIG. 16. FIG. 1 to FIG. 16 are schematic, cross-sectional diagrams showing an exemplary method for fabricating a package-on-package (PoP) assembly according to one embodiment of the invention.

As shown in FIG. 1, a carrier **300** is prepared. The carrier **300** may be a releasable substrate material with an adhesive layer (not explicitly shown), but not limited thereto. At least a dielectric layer or a passivation layer **310** is then formed on a top surface of the carrier **300**. The passivation layer **310** may comprise organic materials such as polyimide (PI) or inorganic materials such as silicon nitride, silicon oxide or the like.

As shown in FIG. 2, subsequently, a redistribution layer (RDL) **410** is formed on the passivation layer **310**. The RDL **410** may comprise at least one dielectric layer **412** and at least one metal layer **414**. The dielectric layer **412** may comprise organic materials such as polyimide (PI) or inorganic materials such as silicon nitride, silicon oxide or the like, but not limited thereto. The metal layer **414** may comprise aluminum, copper, tungsten, titanium, titanium nitride, or the like.

According to the illustrated embodiment, the metal layer **414** may comprise a plurality of first bump pads **415a** and second bump pads **415b** exposed from a top surface of the dielectric layer **412**. The first bump pads **415a** are disposed within a chip mounting area **102**, while the dummy pads **415b** are disposed outside the chip mounting area such as a peripheral area **104** around the chip mounting area **102**. Subsequently, a passivation layer **413** such as polyimide or solder mask material may be formed on the dielectric layer **412**.

As shown in FIG. 3, a lithographic process and an etching process may be performed to form a plurality of openings **413a** and **413b** in the passivation layer **413**. The openings **413a** and **413b** expose the respective first and second bump pads **415a** and **415b**. A conformal conductive layer **416** such

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as Under Bump Metallurgy (UBM) is then formed on the passivation layer **413** and in the openings **413a** and **413b**. For example, the conformal conductive layer **416** may comprise copper or nickel, but not limited thereto.

As shown in FIG. **4**, a photoresist layer **510** is then coated on the conformal conductive layer **416**. The photoresist layer **510** is patterned, for example, by using conventional lithographic processes, to thereby form a plurality of openings **510a** and **510b** directly above the openings **413a** and **413b**, respectively.

As shown in FIG. **5**, a plating process is then performed to fill the openings **510a** and **510b** and the openings **413a** and **413b** with conductive studs **514a** and **514b**. According to the illustrated embodiment, the aforesaid plating process may comprise a copper electroplating process, but not limited thereto. The conductive studs **514a** and **514b** are separated from one another. According to the illustrated embodiment, the conductive studs **514a** may comprise copper, aluminum, tungsten, titanium, titanium nitride, or the like. The conductive studs **514b** may comprise copper, aluminum, tungsten, titanium, titanium nitride, or the like.

As shown in FIG. **6**, another photoresist layer **520** is then coated on the photoresist layer **510** and on the conductive studs **514a** and **514b**. The photoresist layer **520** is patterned, for example, by using conventional lithographic processes, to thereby form a plurality of openings **520b** directly above the conductive studs **514b**, respectively. At this point, the conductive studs **514a** are covered with the photoresist layer **510** and are not exposed.

As shown in FIG. **7**, another plating process is then performed to fill the openings **520b** with conductive studs **524b**. According to the illustrated embodiment, the aforesaid plating process may comprise a copper electroplating process, but not limited thereto. The conductive studs **524b** are only formed within the openings **520b**. According to the illustrated embodiment, the conductive studs **524b** may comprise copper, aluminum, tungsten, titanium, titanium nitride, or the like.

As shown in FIG. **8**, the photoresist layer **520** and the photoresist layer **510** are completely removed to expose the conductive studs **514a** and **514b**, and the conductive studs **524b**. The conductive studs **514b** and **524b** constitute a conductive pillar **624**. Subsequently, an etching process is performed to selectively remove the conformal conductive layer **416** from the top surface of the passivation layer **413**. At this point, each of the conductive pillars **624** consisting of the stacked conductive studs **514b** and **524b** in the peripheral area **104** is higher than the conductive studs **514a** in the chip mounting area **102**.

As shown in FIG. **9**, subsequently, individual flip-chips or dies **420a** and **420b** with their active sides facing down toward the RDL **410** are then mounted on the conductive studs **514a** in the chip mounting area **102** to thereby forming a stacked chip-to-wafer (C2 W) construction. The dies **420a** and **420b** are connected to the conductive studs **514a** through respective terminals **421** distributed on their flipped active surfaces. These individual flip-chips or dies **420a** and **420b** may be active integrated circuit chips with certain functions, for example, GPU (graphic processing unit), CPU (central processing unit), memory chips, etc.

Optionally, an underfill (not shown) may be applied under each chip **420a/420b**. It is respectfully noted that the conductive pillars **624** has a top surface that is lower than the top surface of the dies **420a** and **420b**.

As shown in FIG. **10**, after the chip-bonding process, a molding compound **500** is applied. The molding compound **500** covers the attached active chips **420a** and **420b**, the

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protruding conductive pillars **624**, and the top surface of the passivation layer **413**. The molding compound **500** may be subjected to a curing process. The mold compound **500** may comprise a mixture of epoxy and silica fillers, but not limited thereto.

As shown in FIG. **11**, optionally, the top surface of the mold compound **500** may be subjected to a grinding process to thereby remove an upper portion of the mold compound **500**. At this point, the top surfaces of the active chips **420a** and **420b** may be flush with the top surface of the molding compound **500**.

Subsequently, a laser drilling process is performed to form openings **502b** in the molding compound **500**, to thereby expose a top surface of each of the conductive pillars **624**. It is understood that the openings **502b** may be formed by other methods, such as mechanical drilling or etching. A tapered sidewall profile may be present in the openings **502b**. The dimension of the opening **502b** is wider at the top surface of the mold compound **500** and is narrower at the bottom near the conductive pillars **624**.

As shown in FIG. **12**, another plating process is then performed to fill the openings **502b** with conductive material to thereby form a partial through-mold-via (partial TMV) **504b**. According to the illustrated embodiment, the aforesaid plating process may comprise a copper electroplating process, but not limited thereto. The partial TMVs **504b** are only formed within the respective openings **500b**. According to the illustrated embodiment, the conductive material may comprise copper, aluminum, tungsten, titanium, titanium nitride, or the like.

It is advantageous to use the present invention because the openings **502b** for forming the partial TMVs has smaller aspect ratio, therefore the process window is increased and throughput and quality (yield) of the fabrication process may be improved.

According to the illustrated embodiment, the partial TMV **504b** and the conductive pillar **624** constitute a peripheral bump structure **724** penetrating through the entire thickness of the mold compound **500**. The partial TMV **504b** has a tapered profile that conforms to the tapered profile of each of the openings **502b**. Since the partial TMV **504b** has a smaller width at its bottom, an undercut **725** may be formed between the partial TMV **504b** and the conductive pillar **624**.

As shown in FIG. **13**, subsequently, a carrier **600** is attached to the mold compound **500**. The top surface of the peripheral bump structure **724** is in direct contact with the carrier **600**. The carrier **600** may be a releasable substrate material with an adhesive layer (not explicitly shown), but not limited thereto. The carrier **600** provides temporary support. Thereafter, the carrier **300** is removed to thereby expose a major surface of the passivation layer **310**. The RDL **410** and the passivation layer **310** may function as an interposer **400**. The de-bonding of the carrier **300** may be performed by using a laser process or UV irradiation process, but not limited thereto.

As shown in FIG. **14**, after de-bonding the carrier **300**, openings may be formed in the passivation layer **310** to expose respective solder pads **412a**, and then solder bumps (e.g. C4) or solder balls (e.g. BGA balls) **520** may be formed on the respective solder pads **412a**. Optionally, a dielectric layer or a solder mask **530** may be formed on the passivation layer **310** before forming the solder balls **520**.

As shown in FIG. **15**, subsequently, the carrier **600** is removed to expose the top surface of the peripheral bump structure **724**. The wafer level package is then diced and singulated into individual die package **10**. For example, before dicing, the wafer level package may be first attached

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to a dicing tape **650**, where the bumps **520** face toward, and may contact, the dicing tape **650**.

As shown in FIG. **16**, a die package **20** comprising at least a molded semiconductor die **201** is mounted on the die package **10** to thereby form a PoP assembly **1**. The molded semiconductor die **201** may comprise a DRAM chip, but not limited thereto. The die package **20** may comprise a plurality of BGA balls **250** aligned with the peripheral bump structure **724**. The die package **20** may be electrically connected to the die package **10** through the peripheral bump structure **724** and the RDL **410**.

Those skilled in the art will readily observe that numerous modifications and alterations of the device and method may be made while retaining the teachings of the invention. Accordingly, the above disclosure should be construed as limited only by the metes and bounds of the appended claims.

What is claimed is:

1. A package-on-package (PoP) assembly, comprising:
 - a bottom die package comprising:
 - an interposer having a first side and a second side opposite to the first side;
 - at least one chip mounted on the first side within a chip mounting area through a plurality of bumps;
 - a molding compound disposed on the first side, the molding compound being adjacent to the at least one chip;
 - a plurality of peripheral bump structures penetrating through the molding compound within the peripheral area, wherein each of the peripheral bump structures comprises a conductive pillar embedded in the mold-

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ing compound and a partial through-mold-via (partial TMV) directly stacked on the conductive pillar, wherein the conductive pillar comprises a first conductive stud and a second conductive stud stacked on the first conductive stud; and

a plurality of solder balls mounted on the second side; a top die package mounted on the bottom die package and connected to the peripheral bump structures.

2. The PoP assembly according to claim **1**, wherein the interposer comprises a redistribution layer (RDL).

3. The PoP assembly according to claim **2**, wherein the RDL comprises at least one dielectric layer and at least one metal layer.

4. The PoP assembly according to claim **1**, wherein the top die package comprises at least a molded semiconductor die.

5. The PoP assembly according to claim **1**, wherein a top surface of the conductive pillar is higher than that of the bumps.

6. The PoP assembly according to claim **1**, wherein an undercut is present between the conductive pillar and the partial TMV.

7. The PoP assembly according to claim **1**, wherein the first conductive stud comprises copper, aluminum, tungsten, titanium, or titanium nitride.

8. The PoP assembly according to claim **7**, wherein the second conductive stud comprises copper, aluminum, tungsten, titanium, or titanium nitride.

9. The PoP assembly according to claim **1**, wherein the partial TMV comprises copper, aluminum, tungsten, titanium, or titanium nitride.

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